

Surface Sensitive X-ray Scattering



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Introduction

- Concepts of surfaces
- Scattering (Born approximation)
- **Crystal Truncation Rods**
 - The basic idea
 - How to calculate
 - Examples

Reflectivity

- In Born approximation
- Exact formalism (Fresnel)
- Examples

Grazing Incidence Diffraction

- The basic idea
- Penetration depth
- Example

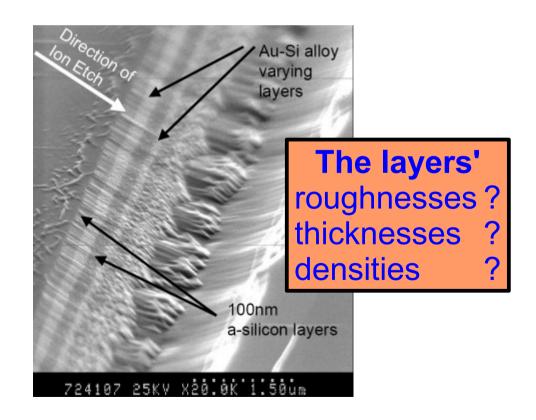
With x-ray and neutron reflectivity surfaces, buried interfaces and the properties of thin film systems can be investigated on a micro- and nanoscale.

Fundamental science, e.g.:

- layer growth
- roughness evolution

Industrial applications, e.g.:

- semiconductor devices
- storage devices / harddisks
- coatings
- Iubricants
- catalysts







Advantages of x-ray and neutron reflectometry:

- Resolution in the Å-regime
- Gives a lot of information with just one measurement
- Usually non-destructive
- Highly element specific
- No special preparation of the sample
- (Averaged information over whole sample area)

Disadvantages of x-ray and neutron reflectometry:

- No unique results without preknowledge
- No fast results
- Interpretation/analysis often not easy
- (No local information)

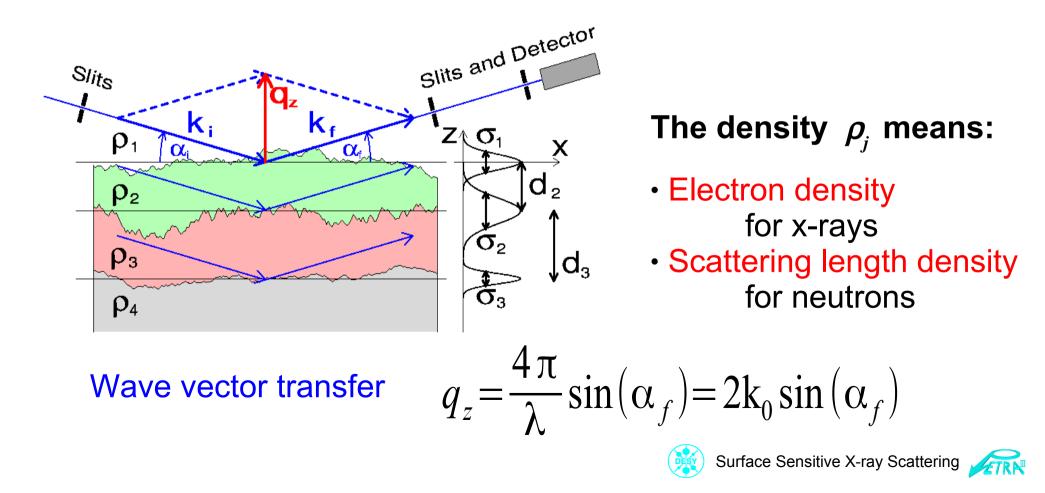


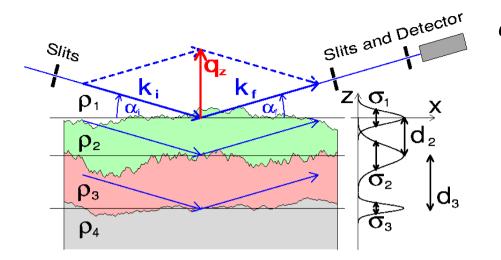


Theoretical Part

a) General Considerations

Photons with wavelength λ (or neutrons with $\lambda = h/\sqrt{2mE}$) are scattered elastically (no energy change: $\lambda_i = \lambda_f$) at the surface. The incident angle α_i equals the exit angle α_f .

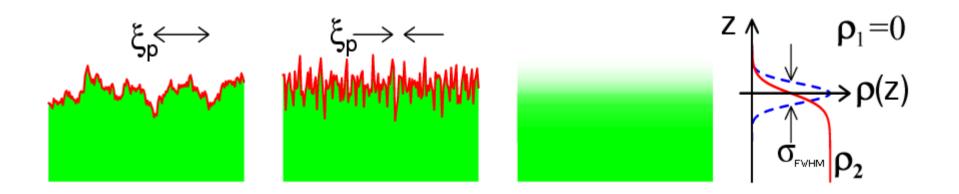




 q_{z} is perpendicular to the surface

only sensitive to information perpendicular to the surface : electron (scattering length) density profile $<\rho(x,y,z)>_{(x,y)} = \rho(z)$.

That means: a reflectivity cannot distinguish different in-plane structures.

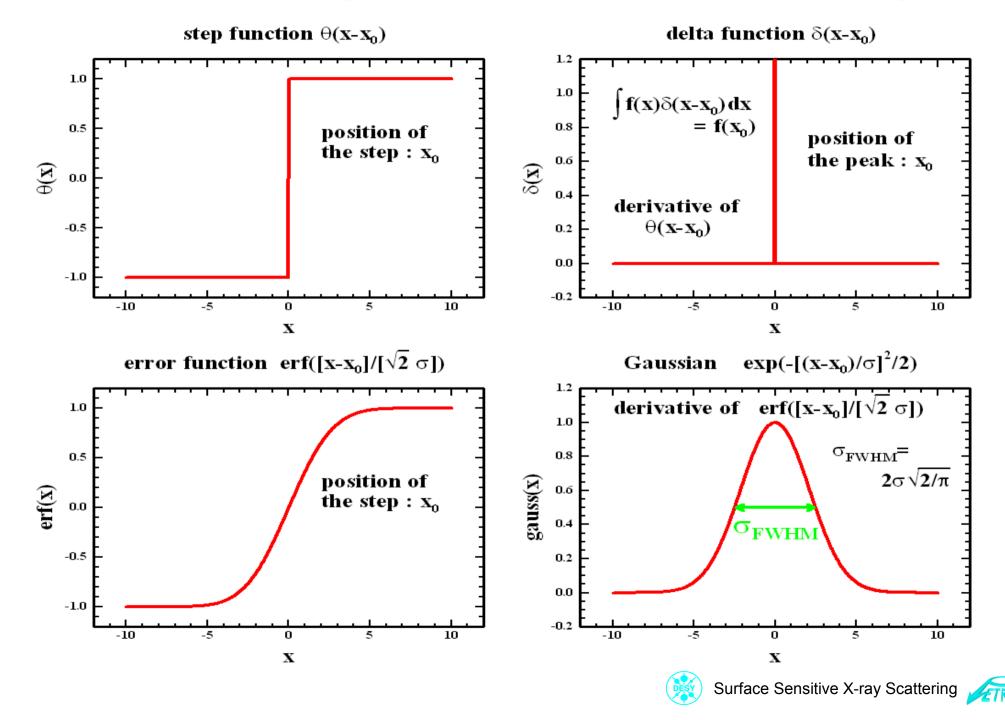


These different surfaces have the same reflectivity !





The following functions are important in the following:



Specularly Reflected Intensity in
Born Approximation
$$(I_{scatt} << I_0)$$

 $I(q_z) \propto \frac{1}{q_z^4} \left| \int \frac{d\rho(z)}{dz} \exp(iq_z z) dz \right|^2$

Given by the absolute square of the Fouriertransformation of the derivative of the density/(scattering length) profile and divided by q_z^4 .

Consequences:

- Reflected intensity drops fast with increasing angle : 1
- Only differences in density can be seen (contrast)
- Only sensitive to density properties in z-direction
- No direct picture visible
- Phase information gets lost \Rightarrow no unique solution : At

- $1/q_z^4$
 - : Derivative
 - : Density profile
 - : Fourier space
 - : Absolute square



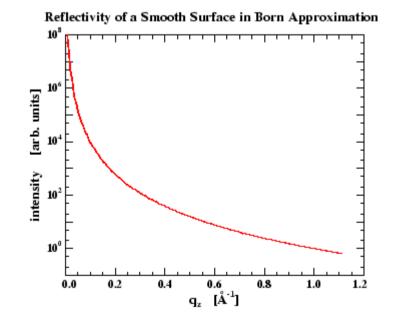


Examples



Density profile:
$$\rho(z) = \frac{\rho_2}{2} (1 - \Theta[z]) \Rightarrow \frac{d\rho}{dz} \propto \delta(z)$$

$$\begin{split} I(q_{z}) \propto &\frac{1}{q_{z}^{4}} \left| \int \frac{d\rho(z)}{dz} \exp(iq_{z}z) dz \right|^{2} \\ &= &\frac{1}{q_{z}^{4}} \left| \int \delta(z) \exp(iq_{z}z) dz \right|^{2} \\ &= &\frac{1}{q_{z}^{4}} \left| \exp(iq_{z} \cdot 0) \right|^{2} = &\frac{1}{q_{z}^{4}} \cdot |1|^{2} = &\frac{1}{q_{z}^{4}} \end{split}$$







2) single smooth surface at $z = z_1$ (shifted)

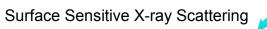
vacuum
$$\rho_1=0$$
substrate ρ_2
 z
 z
 z
 z
 z_1

Density profile:
$$\rho(z) = \frac{\rho_2}{2} (1 - \Theta[z - z_1]) \Rightarrow \frac{d\rho}{dz} \propto \delta(z - z_1)$$

$$\begin{split} I(q_z) \propto & \frac{1}{q_z^4} \left| \int \frac{d\,\rho(z)}{dz} \exp(iq_z z) \, dz \right|^2 = \frac{1}{q_z^4} \left| \int \delta(z - z_1) \exp(iq_z z) \, dz \right|^2 \\ &= \frac{1}{q_z^4} \left| \exp(iq_z z_1) \right|^2 = \frac{1}{q_z^4} \cdot 1^2 = \frac{1}{q_z^4} \end{split}$$

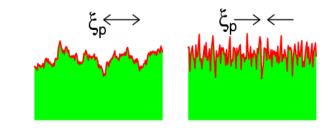
A shift of the sample does not change the reflectivity.







3) single rough surface with roughness σ



$$z \wedge \rho_1 = 0$$

$$\downarrow \rho_1 = 0$$

$$\downarrow \rho_2$$

Density profile:
$$\rho(z) = \frac{\rho_2}{2} \left[1 - \operatorname{erf}\left(\frac{z}{\sqrt{2}\sigma}\right) \right] \Rightarrow \frac{d\rho}{dz} \propto \exp\left(\frac{-z^2}{2\sigma^2}\right)$$

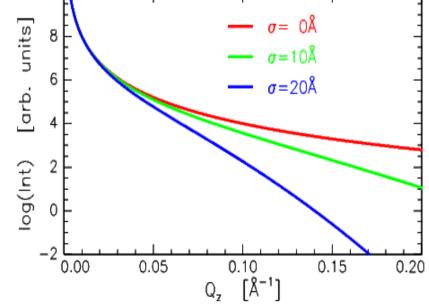
$$I(q_z) \propto \frac{1}{q_z^4} \left| \int \frac{d\rho(z)}{dz} \exp(iq_z z) dz \right|^2$$
$$= \frac{1}{q_z^4} \left| \int \exp\left(\frac{-z^2}{2\sigma^2}\right) \exp(iq_z z) dz \right|^2$$

Fourier transformation is known!

$$\propto \frac{1}{q_z^4} \left| \exp\left(\frac{-q_z^2 \sigma^2}{2}\right) \right|^2 = \frac{1}{q_z^4} \exp\left(-q_z^2 \sigma^2\right)$$

Debye-Waller factor

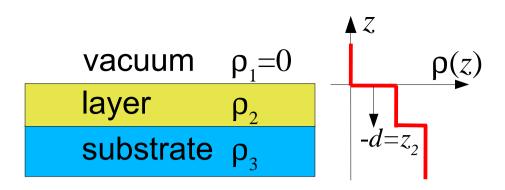
Effect of the roughness







4) single smooth layer with thickness *d*



Density profile:
$$\rho(z) = \frac{\Delta \rho_1}{2} [1 - \Theta(z)] + \frac{\Delta \rho_2}{2} [1 - \Theta(z + d)]$$

Derivative of $\rho(z)$: $\frac{d \rho}{dz} \propto \Delta \rho_1 \delta(z) + \Delta \rho_2 \cdot \delta(z + d)$ with: $\frac{\Delta \rho_1 = \rho_2 - \rho_1}{\Delta \rho_2 = \rho_3 - \rho_2}$

$$I(q_{z}) \propto \frac{1}{q_{z}^{4}} \left| \int \frac{d\rho(z)}{dz} \exp(iq_{z}z) dz \right|^{2} = \frac{1}{q_{z}^{4}} \left| \int [\Delta\rho_{1}\delta(z) + \Delta\rho_{2}\delta(z+d)] \exp(iq_{z}z) dz \right|^{2}$$

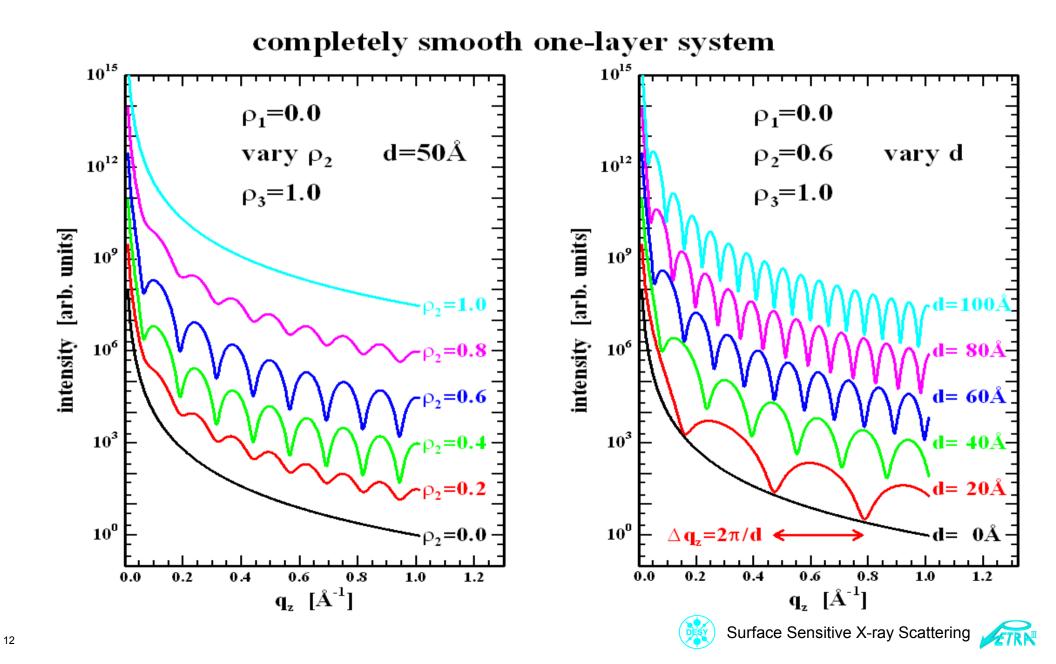
$$= \frac{1}{q_{z}^{4}} |\Delta\rho_{1} + \Delta\rho_{2} \exp(-iq_{z}d)|^{2} = \frac{1}{q_{z}^{4}} [\Delta\rho_{1} + \Delta\rho_{2} \exp(iq_{z}d)] \cdot [\Delta\rho_{1} + \Delta\rho_{2} \exp(-iq_{z}d)]$$

$$= \frac{1}{q_{z}^{4}} (\Delta\rho_{1}^{2} + \Delta\rho_{2}^{2} + \Delta\rho_{1}\Delta\rho_{2} [\exp(iq_{z}d) + \exp(-iq_{z}d)])$$

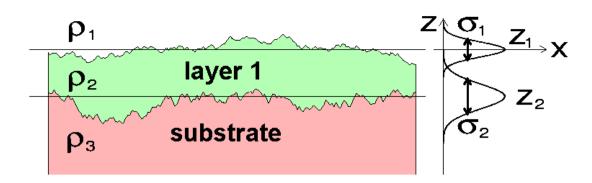
$$= \frac{1}{q_{z}^{4}} [\Delta\rho_{1}^{2} + \Delta\rho_{2}^{2} + 2\Delta\rho_{1}\Delta\rho_{2} \cos(q_{z}d)]$$
oscillating function

$$Surface Sensitive X-ray Scattering$$

• Contrasts $\Delta \rho_1$ and $\Delta \rho_2$ determine the visibility of the oscillations. • Film thickness *d* determines the period via $\Delta q_2 = 2\pi/d$.



5) single layer with rough interfaces and thickness $d = -z_2$



Density profile:
$$\rho(z) = \frac{\Delta \rho_1}{2} \left[1 - \operatorname{erf}\left(\frac{z - z_1}{\sqrt{2} \sigma_1}\right) \right] + \frac{\Delta \rho_2}{2} \left[1 - \operatorname{erf}\left(\frac{z - z_2}{\sqrt{2} \sigma_2}\right) \right]$$

Derivative of $\rho(z)$:
$$\frac{d \rho}{dz} \propto \frac{\Delta \rho_1}{\sigma_1} \exp\left(\frac{-(z - z_1)^2}{2 \sigma_1^2}\right) + \frac{\Delta \rho_2}{\sigma_2} \exp\left(\frac{-(z - z_2)^2}{2 \sigma_2^2}\right)$$

using:
$$\int \exp\left(\frac{-(z - z_1)^2}{2 \sigma_1^2}\right) \exp(iq_z z) dz = \exp(iq_z z_1) \sqrt{2} \sigma_1 \exp\left(\frac{q_z^2 \sigma_1^2}{2}\right)$$

Result:
$$I(q_z) \propto \frac{1}{q_z^4} \left[\Delta \rho_1^2 \exp(-q_z^2 \sigma_1^2) + \Delta \rho_2^2 \cdot \exp(-q_z^2 \sigma_2^2) + 2\Delta \rho_1 \Delta \rho_2 \exp\left(-q_z^2 \frac{\sigma_1^2 + \sigma_2^2}{2}\right) \cos(q_z z_2) \right]$$

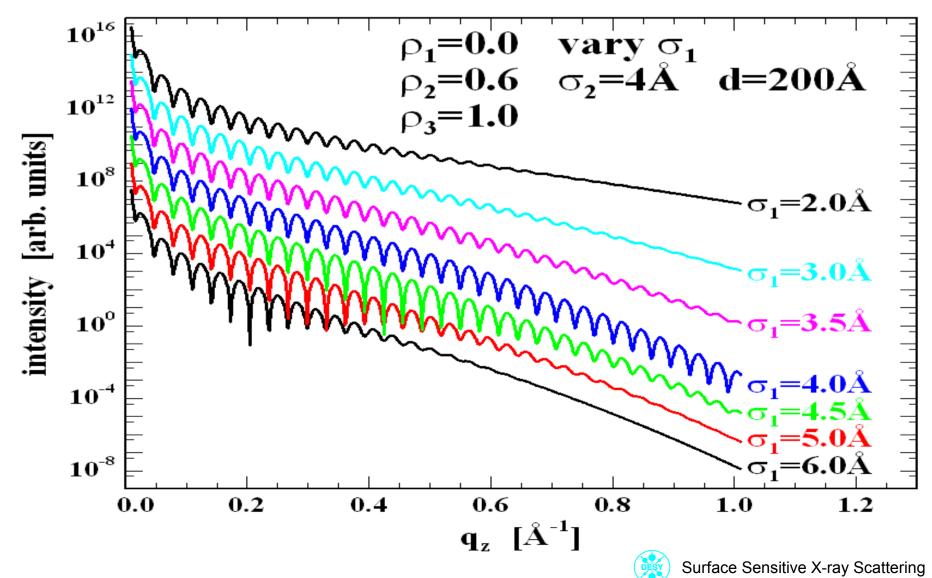


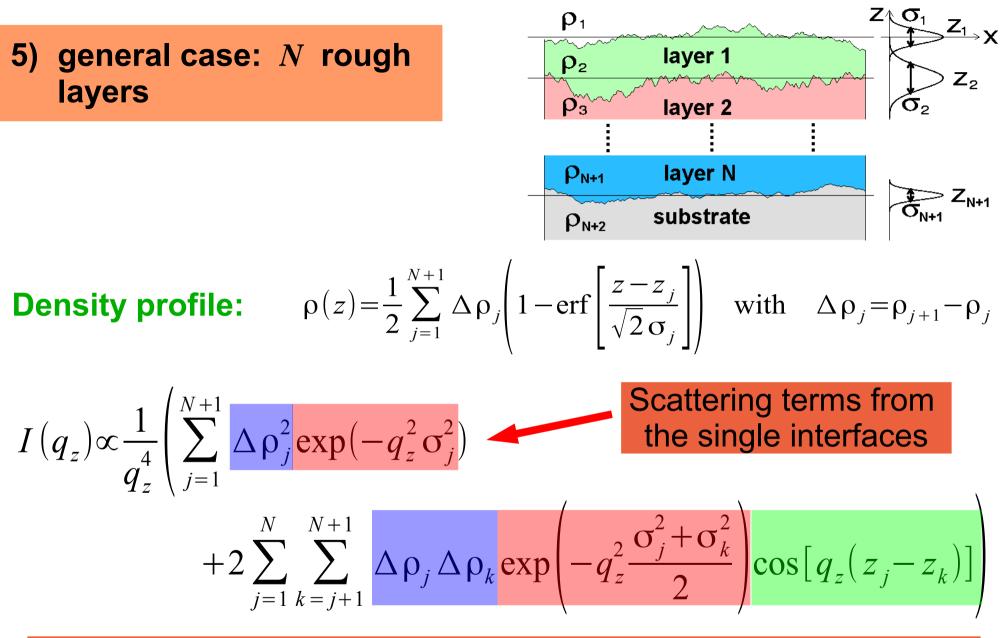


• At large q_z the scattering is dominated by the smoothest interface. • The difference between the σ 's of a layer determines the "die-out"

of the oscillations.





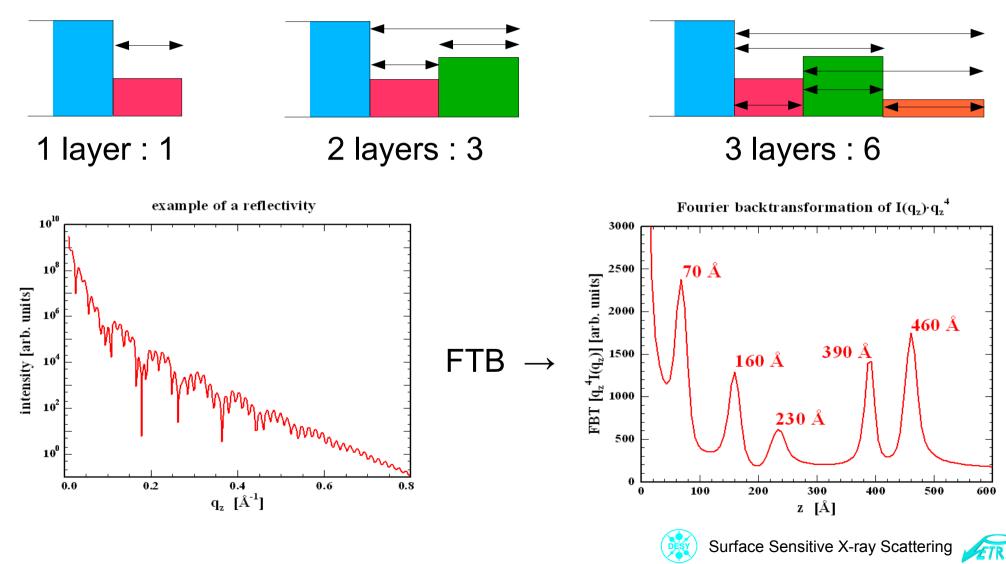


Each distance $z_j - z_k$ gives an oscillating term, scaled with the respective Debye-Waller factor and the contrasts at the interfaces.

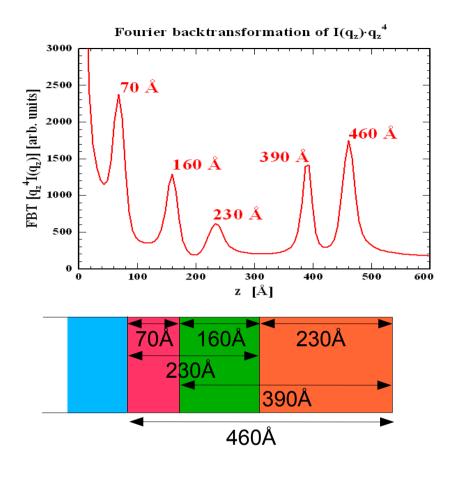




For a first guess on reflectivity data: Fourier backtransformation of $q_z^4 \cdot I(q_z)$ will show distinct peaks for each oscillation (\Leftrightarrow distance).



Maximum number of distances



Only 5 peaks !

Likely a 3-layer system with one layer thickness matching the sum of two neighboring layers.

Two possibilities:

